

TTTC News

The TTTC website always lists the latest features and information for its visitors! To find out more, please visit the website at http://www.ieee-tttc.org/.

PAST TTTC EVENTS

The 24th European Test Symposium 27–31 May 2019 Baden-Baden, Germany https://www.testgroup.polito.it/ets19/

The IEEE European Test Symposium (ETS) is Europe's premier forum dedicated to presenting and discussing scientific results, emerging ideas, applications, hot topics, and new trends in the area of electronic-based circuits and system testing, reliability, security, and validation. In 2019, ETS took place in the Congress Center in Baden-Baden. It was organized by the Karlsruhe Institute of Technology (KIT), Karlsruhe, Germany, which cosponsored the event jointly with the IEEE Council on Electronic Design Automation (CEDA). In addition to scientific paper submissions, this year ETS also offered an embedded workshop dedicated to work in progress and case studies as well as a PhD forum. The special track on emerging test strategies (ETS2) again focused on upcoming problems and ideas in an industrial context. A Test Spring School was organized in conjunction with ETS'19.

The 25th International Symposium on On-Line Testing and Robust System Design (IOLTS'19)

1–3 July 2019 Rhodes, Greece http://tima.univ-grenoble-alpes.fr/conferences/ iolts/iolts19/index.php

Issues related to online testing techniques, and more generally to design for robustness, are

Digital Object Identifier 10.1109/MDAT.2019.2927361 Date of current version: 1 October 2019.

increasingly important in modern electronic systems. In particular, the huge complexity of electronic systems has led to growth in reliability needs in several application domains as well as the pressure for low-cost products. There is a corresponding increasing demand for a cost-effective design for robustness techniques. These needs have increased dramatically with the introduction of nanometer technologies, which adversely impact noise margins; process, voltage, and temperature variations; aging and wear-out; soft error and EMI sensitivity; power density and heating; and make mandatory the use of design for robustness techniques for extending, yield, reliability, and lifetime of modern SoCs. Design for reliability has become mandatory for reducing power dissipation, as voltage reduction—often used to reduce power—strongly affects reliability by reducing noise margins and the sensitivity to soft-errors and EMI, and by increasing circuit delays and the severity of timing faults. There is also a strong relation between Design for Reliability and Design for Security, as security attacks are often fault-based.

The International Symposium on On-Line Testing and Robust System Design (IOLTS) is an established forum for presenting novel ideas and experimental data on these areas. The Symposium is sponsored by the IEEE CEDA, and the 2019 edition was organized by the IEEE Computer Society Test Technology Technical Council, the University of Athens, and the TIMA Laboratory.

UPCOMING TTTC EVENTS

The 32nd IEEE International Symposium on Defect and Fault Tolerance in VLSI and Nanotechnology Systems (DFT'19) 2–4 October 2019

Delft, The Netherlands http://www.dfts.org/

DFT is an annual symposium providing an open forum for presentations in the field of defect and fault tolerance in VLSI and nanotechnology systems inclusive of emerging technologies. One of the unique features of this symposium is to combine new academic research with state-of-the-art industrial data, which is an essential factor for significant advances in this field. All aspects of design, manufacturing, test, reliability, and availability that are affected by defects during manufacturing and by faults during system operation are of interest. Topics include (but are not limited to) Yield Analysis and Modeling; Testing Techniques; Design for Testability in IC Design; Error Detection, Correction, and Recovery; Dependability Analysis and Validation; Repair, Restructuring, and Reconfiguration; Defect and Fault Tolerance; Radiation Effects; Aging and Lifetime Reliability; Dependable Applications and Case Studies; Emerging Technologies; and Design for Security.

The IEEE International Test Conference (2019)

12–14 November 2019 Washington, D.C., USA http://www.itctestweek.org/about-itc/

The International Test Conference (ITC) is the world's premier venue dedicated to the electronic test of devices, boards, and systems—covering the complete cycle from design verification, design-fortest, design-for-manufacturing, silicon debug, manufacturing test, system test, diagnosis, reliability and failure analysis, and back to process and design improvement. At ITC, design, test, and yield professionals can confront challenges faced by the industry and learn how these challenges are being addressed by the combined efforts of academia, design tool and equipment suppliers, designers, and test engineers. As the cornerstone of the Test Week event, ITC offers a wide variety of technical activities targeted at test and design theoreticians and practitioners, including formal paper sessions, tutorials, panel sessions, case studies, invited lectures, commercial exhibits and presentations, and a host of ancillary professional meetings.

NEWSLETTER EDITOR'S INVITATION

I would appreciate input and suggestions about the newsletter from the test community. Please forward your ideas, contributions, and information on awards, conferences, and workshops to Theocharis (Theo) Theocharides, Department of Electrical and Computer Engineering, University of Cyprus, 75 Kallipoleos Avenue, PO Box 20537, Nicosia 1678, Cyprus; ttheocharides@ucy.ac.cy. Theo Theocharides Editor, TTTC Newsletter

BECOME A TTTC MEMBER

For more details and free membership, browse the TTTC web page: http://tab.computer.org/tttc.

CONTRIBUTIONS TO THIS NEWSLETTER: Send contributions to Theocharis (Theo) Theocharides, Department of Electrical and Computer Engineering, University of Cyprus, 75 Kallipoleos Avenue, PO Box 20537, Nicosia 1678, Cyprus; ttheocharides@ucy. ac.cy. For more information, see the TTTC web page: http://tab.computer.org/tttc.